

# **Notice of References Cited**

Application/Control  
09/826,827

Applicant(s)/Patent Under  
Reexamination  
IKURUMI ET AL

Examiner  
Justin P. Bettendorf

Art Unit  
2817

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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0003496 A1	01-2002	Brady et al.	343/700.0MS
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ponchak et al., "Open- and Short-Circuit Terminated Series Stubs in Finite-Width Coplanar Waveguide on Silicon," June 1997, IEEE Transactions on Microwave Theory and Techniques, Vol. 45, No. 6, pp.970-976.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,028,564	02-2000	Duan et al.	343/818
	B	US-4,825,220	04-1989	Edward et al.	343/795
	C	US-6,343,369	01-2002	Saunders et al.	716/4
	D	US-		/	
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,169,301	01-2001	Ishikawa et al.	257/275
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
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